

09/19/00

| | | | |
|--|-------|----------|----------------------|
| | | Subclass | ISSUE CLASSIFICATION |
| | Class | | |

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. PATENT DATE
AC S(4) Q.A. JPT
SCANNED _____ Q.A. _____

| | | | | | |
|------------------------------|-----------------|---------------------|-----------------|--------------------------|---------------------|
| APPLICATION NO. 09/664643 | CONT/PRIOR F | CLASS 349 174 | SUBCLASS 261 | ART UNIT 2874 28-1 | EXAMINER NOZRIS. |
|------------------------------|-----------------|---------------------|-----------------|--------------------------|---------------------|

ANTS Koichi Miyasaka

Conductor-pattern testing method, and electro-optical device

PTO-2040
10/09

ISSUING CLASSIFICATION

WARNING:

The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-438A
(Rev. 6/99)

FILED WITH: DISK (CRF) FICHE CD-ROM

(Attached in pocket on right inside flap)

For more information about the study, please contact Dr. John P. Morrissey at (212) 639-7330 or via e-mail at jmorrissey@nyp.edu.

(FACE)